Notice of References Cited Application/Control No. 10/527,036 Applicant(s)/Patent Under Reexamination TANAKA ET AL. Examiner Anh T. Mai Application/Control No. Applicant(s)/Patent Under Reexamination TANAKA ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,407,343	06-2002	Tanaka, Shinji	174/261
*	В	US-6,304,164	10-2001	Ohno et al.	336/200
*	С	US-6,249,205	06-2001	Meadors et al.	336/200
*	D	US-5,985,414	11-1999	Fukuda et al.	428/192
*	Ε	US-5,404,118	04-1995	Okamura et al.	333/175
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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